SCAS156A - NOVEMBER 1990 - REVISED APRIL 1993

- Inputs Are TTL-Voltage Compatible
- Provides Extra Data Width Necessary for Wider Address/Data Paths or Buses With Parity
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Ceramic 300-mil DIPs

description

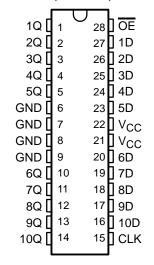
These 10-bit flip-flops feature 3-state outputs designed specifically for driving highly-capacitive or relatively low-impedance loads. They are particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers with parity, and working registers.

On the positive transition of the clock the Q outputs will follow the D inputs.

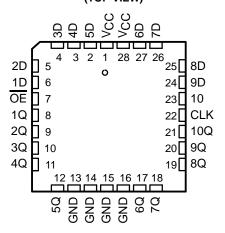
A buffered output enable (\overline{OE}) input can be used to place the ten outputs in either a normal logic state (high or low level) or a high-impedance state. In the high-impedance state the outputs neither load nor drive the bus lines significantly.

The high-impedance state and increased drive provide the capability to drive the bus lines in a bus-organized system without need for interface or pull-up components.

54ACT11821 . . . JT PACKAGE 74ACT11821 . . . DW PACKAGE (TOP VIEW)



54ACT11821 . . . FK PACKAGE (TOP VIEW)



The output enable (OE)does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

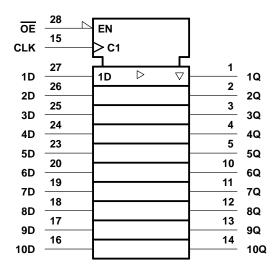
The 54ACT11821 is characterized for operation over the full military temperature range of -55° C to 125°C. The 74ACT11821 is characterized for operation form -40° C to 85°C.

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FUNCTION TABLE (each flip-flop)

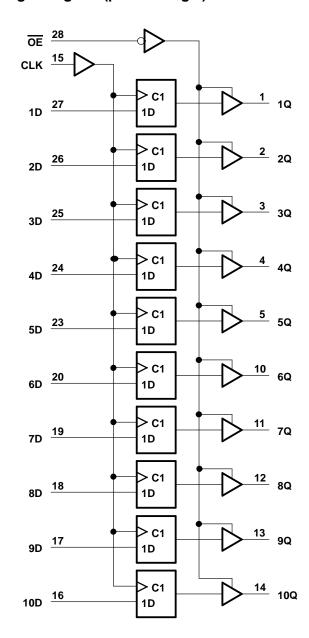
	INPUTS	OUTPUT	
OE	CLK	D	Q
L	1	Н	Н
L	\uparrow	L	L
L	L	Χ	Q_0
L	Н	Χ	Q ₀ Q ₀ X ₀
L	\downarrow	Χ	x ₀
Н	X	Χ	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



Pin numbers shown are for the DW, JT, and NT packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	\dots -0.5 V to 7 V
Input voltage range, V _I (see Note 1)	V to $V_{CC} + 0.5 V$
Output voltage range, V _O (see Note 1)	$V \text{ to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	$\dots \dots \pm 20 \text{ mA}$
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V _{CC} or GND	±250 mA
Storage temperature range	−55°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

		54ACT11821		74ACT11821			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		151	2			V
V _{IL}	Low-level input voltage		ZE,	0.8			0.8	V
٧ _I	Input voltage	0	2	VCC	0		VCC	V
۷o	Output voltage	0	5	VCC	0		VCC	V
IOH	High-level output current	Ċ	9	-24			-24	mA
l _{OL}	Low-level output current	ti _Q		24			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10			10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS		Т,	Δ = 25°C	;	54ACT	11821	74ACT11821		UNIT
PARAMETER		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
	I _{OH} = -50 μA	4.5 V	4.4			4.4		4.4		٧
		5.5 V	5.4			5.4		5.4		
Vari	lou - 24 mA	4.5 V	3.94			3.7		3.8		
VOH	$I_{OH} = -24 \text{ mA}$	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85	2			
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V					75,	3.85		
	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
		5.5 V			0.1		0.1		0.1	
Val	I _{OL} = 24 mA	4.5 V			0.36	, '2'	0.5		0.44	
VOL		5.5 V			0.36	Q _C	0.5		0.44	
	I _{OL} = 50 mA [†]	5.5 V				Y _Q	1.65			
	I _{OL} = 75 mA [†]	5.5 V							1.65	
ΙĮ	V _I = V _{CC} or GND	5.5 V			±0.1		±1		±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		160		80	μΑ
∆l _{CC} ‡	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			0.9		1		1	mA
C _i	V _I = V _{CC} or GND	5 V		4.5						pF
Co	$V_O = V_{CC}$ or GND	5 V		12						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, $\rm V_{CC}$ = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

		T _A = 25°C		54ACT11821	21 74ACT11821		UNIT
		MIN	MAX	MIN MAX	MIN	MAX	UNIT
fclock	Clock frequency	0	125	0 2 125	0	125	MHz
t _W	Pulse duration, CLK high or low	4		4)	4		ns
t _{su}	Setup time, data before CLK↑	2.5		2.5	2.5		ns
th	Hold time, data after CLK↑	1.5		2 1.5	1.5	, i	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			54ACT11821		74ACT11821		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f _{max}			125			125	EN	125		MHz
^t PLH	CLK	Any Q	4.7	7.6	10.4	4.7	12.6	4.7	11.7	20
^t PHL			5	8.1	11	5 4	12.9	5	12.1	ns
^t PZH	ŌĒ	Any Q	3.1	6.1	9.1	3.1	10.8	3.1	10	ns
^t PZL			4.1	7.6	11	4.1	13.2	4.1	12.3	110
^t PHZ	ŌĒ Any Q	Any O	4.8	7.2	9.2	4.8	10.6	4.8	10.1	ns
^t PLZ		4.8	6.8	8.6	4.8	9.8	4.8	9.4	115	

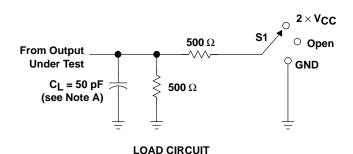


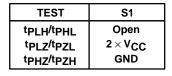
 $[\]ddagger$ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

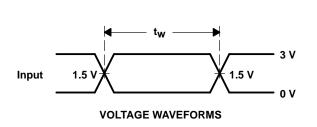
operating characteristics, V_{CC} = 5 V, T_A = 25°C

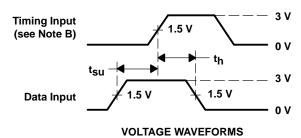
PARAMETER			TEST CON	TYP	UNIT
C _{pd} Power dissipation capacitance per flip-flop	Outputs enabled	C: - 50 pF	f — 1 M⊔→	45	nE
	Power dissipation capacitance per liip-liop	Outputs disabled	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	31	p⊦

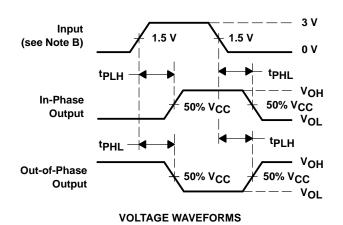
PARAMETER MEASUREMENT INFORMATION

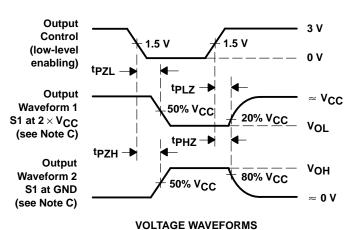












NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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